

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 09/886,063 DILLEN ET AL.	
		Examiner	Art Unit John M. Villecco 2612	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,724,945	04-2004	Yen et al.	348/246
	B	US-5,696,554	12-1997	Hwang, Jeong Hwan	348/246
	C	US-2001/0036305	11-2001	Jun, Sung-Chun	382/149
	D	US-6,707,493	03-2004	Lee et al.	348/246
	E	US-5,805,216	09-1998	Tabei et al.	348/246
	F	US-2003/0063203	04-2003	Ohno, Yoshinori	348/247
	G	US-4,701,784	10-1987	Matsuoka et al.	348/247
	H	US-6,593,961	07-2003	Perino, Stanley C.	348/247
	I	US-6,704,458	03-2004	Ford, Gordon D.	382/275
	J	US-6,104,839	08-2000	Cok et al.	382/254
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001028711 A	01-2001	Japan	ITSUKAICHI, MASAKATSU	H04N 05/335
	O	JP 2001307079 A	11-2001	Japan	ARASAKI et al.	G06T 01/00
	P	GB 2364461 A	01-2002	United Kingdom	YEN et al.	H04N 05/217
	Q	EP 778543 A2	06-1997	European Patent	MATRASZEK et al.	G06T 05/20
	R	JP 10150570 A	06-1998	Japan	MURAKAMI, SHIGEO	H04N 01/409
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.